

Search Notes**Application/Control No.**

10/516,441

Examiner

BIN SHEN

**Applicant(s)/Patent under
Reexamination**

IRTH ET AL.

Art Unit

1657

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
updated search: STN.	3/12/2008	BS